

Author's Publications

Journal Publication

- [1] H. He, Y. Kang, T. Ge, L. Guo, and J. S. Chang
“A 2.5W 40MHz-Bandwidth Hybrid Supply Modulator with 91% Peak Efficiency, 3V Output Swing and 4mV Output Ripple at 3.6V Supply”
IEEE Transactions on Power Electronics, pp. 1-1, 2018.

Conference Publications

- [2] Y. Kang, T. Ge, H. He, and J. S. Chang
“A review of audio Class D amplifiers”
International Symposium on Integrated Circuits (ISIC), Singapore, pp. 1-4, 2016.
- [3] H. He, Y. Kang, J. Yu, L. Guo, T. Ge, and J. S. Chang
“A novel low-power high-efficiency 3-state filterless bang-bang class D amplifier”
IEEE International Conference on Electronics, Circuits, and Systems (ICECS),
Cairo, Egypt, pp. 93-96, 2015.
- [4] T. Ge, J. Zhou, Y. Kang, and J. S. Chang
“Review: A fully-additive printed electronics process with very-low process variations (Bent and unbent substrates) and PDK”
IEEE International Symposium on Circuits and Systems (ISCAS), Baltimore,
Maryland, United States, pp. 1-4, 2017.

- [5] T. Ge, H. He, J. Zhou, Y. Kang, and J. S. Chang
“An Investigation of THD of a BTL Class D Amplifier”
IEEE International Symposium on Circuits and Systems (ISCAS), Montreal, Canada,
pp. 1-4, 2016.
- [6] T. Ge, L. Guo, H. He, Y. Kang, J. Yu, and J. S. Chang,
“Envelope Tracking RF Power Amplifiers: Fundamentals, Design Challenges, and
Unique opportunities offered by LEES-SMART InGaAs-on-CMOS process”
8th International Conference on Materials for Advanced Technologies, Singapore,
2015.
- [7] T. Ge, L. Guo, Y. Kang, J. Zhou, H. HE, P. J. E. Ng, E. Fitzgerald, K. E. K. Lee,
and J. S. Chang
“A driver circuit based on the emerging GaN-on-CMOS process for the emerging
Electroluminescent panels”
IEEE 58th International Midwest Symposium on Circuits and Systems (MWSCAS),
Fort Collins, Colorado, United States, pp. 1-4, 2015.
- [8] L. Guo, T. Ge, Y. Kang, H. He, and J. S. Chang
“Analysis and design of PWM-in-PWM-out Class D Amplifiers”
IEEE 57th International Midwest Symposium on Circuits and Systems (MWSCAS),
College Station, Texas, United States, pp. 254-257, 2014.

- [9] J. S. Chang, K. S. Chong, W. Shu, T. Lin, J. Jiang, K. Z. L. Ne, and Y. Kang
“Radiation-hardened library cell template and its total ionizing dose (TID) delay
characterization in 65nm CMOS process”
IEEE 57th International Midwest Symposium on Circuits and Systems (MWSCAS),
College Station, Texas, United States, pp. 821-824, 2014